



Report No. A2230338580104001

Company Name SEMICONDUCTOR MANUFACTURING NORTH CHINA (BEIJING) CORP.

shown on Report

18 WENCHANG ROAD, BEIJING ECONOMIC-TECHNOLOGICAL DEVELOPMENT Address

AREA, CHINA, 100176

The following sample(s) and sample information was/were submitted and identified by/on the behalf of the

applicant

Sample Name Wafer

Part No. SMNC(BJ) Cu Process 40nm Production Wafer

Sample Received Date Jul. 12, 2023

Testing Period Jul. 12, 2023 to Jul. 15, 2023

As specified by client, to test Antimony(Sb) in the submitted sample(s). **Test Requested**

Test Method Please refer to the following page(s). Test Result(s) Please refer to the following page(s).

mal Pinbiao(Shanghai) Co., Ltd.

Chen kaimin

Lab Manager

Date

Jul. 15, 2023

No. R268854110

No.1351, Wanfang Road, Minhang District, Shanghai, China



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Test Method

Test Item(s)	Test Method	Measured Equipment(s)
Antimony(Sb)	Refer to US EPA 3052:1996 & US EPA 6010D:2018	ICP-OES

Test Result(s)

Tested Item(s)	Result	MDL
	001	
Antimony (Sb)	N.D.	10 mg/kg

Sample/Part Description

No. CTI Sample ID Description
1 001 Wafer

Remark: The sample(s) had been dissolved totally tested for Antimony.

-MDL = Method Detection Limit -N.D. = Not Detected (<MDL) -mg/kg = ppm = parts per million

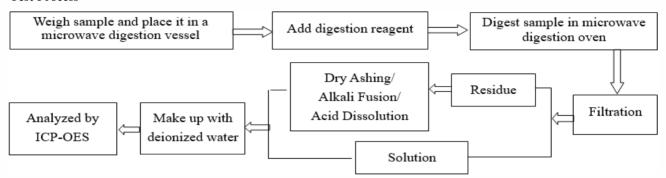






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Test Process



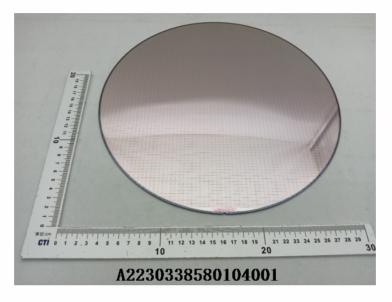






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Photo(s) of the sample(s)



Statement:

- 1. This report is considered invalid without approved signature, special seal and the seal on the perforation;
- 2. The Company Name shown on Report and Address, the sample(s) and sample information was/were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified;
- 3. The result(s) shown in this report refer(s) only to the sample(s) tested;
- 4. Without written approval of CTI, this report can't be reproduced except in full;
- 5. In case of any discrepancy between the English version and Chinese version of the testing reports (if generated), the Chinese version shall prevail.

*** End of report ***